

Form PTO 1449
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New Application

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Hiroyoshi TANIMOTO, et al.

FILING DATE

Herewith

GROUP

11011 U.S. PTO
10/001977

12/05/01

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES	NO
	AO					
	AP					
	AQ					
	AR					
	AS					
	AT					
	AU					
	AV					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

PEP	AW	Robert H. TU, et al., "BERKELEY RELIABILITY TOOLS-BERT", IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems, Vol. 12, No. 10, October 1993, pgs. 1524 - 1534.
PEP	AX	Chenming HU, et al., "HOT-ELECTRON-INDUCED MOSFET DEGRADATION-MODEL, MONITOR, AND IMPROVEMENT", IEEE Transactions on Electron Devices, Vol. ED-32, No. 2, February 1985, pgs. 375 - 385.
	AY	
	AZ	

Examiner

Paula Quinto

Date Considered

2-10-03

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.